

Search Notes

Application/Control No.

10/758,276

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

TAKAHASHI ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-35	12/21/2005	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR